

**Search Notes**

Application/Control No.

10/050,101

Examiner

John Chavis

Applicant(s)/Patent under  
Reexamination

NAKANO, MINORU

Art Unit

2191

**SEARCHED**

| Class | Subclass | Date      | Examiner |
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| 717   | 174      | 7/21/2005 | JC       |
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**INTERFERENCE SEARCHED**

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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|   | DATE      | EXMR |
|---|-----------|------|
| West (IBM TDB, DERWENT, EPO,<br>JPO, USPAT, PGPUBS) | 7/21/2005 | JC   |
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